



SEMITRANS® 5

IGBT4 Modules

Engineering Sample SKM600GAE12E4

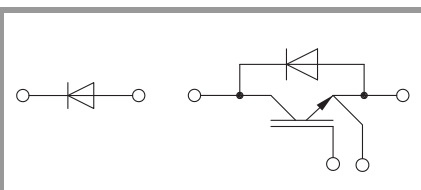
Target Data

Features

- IGBT4 = 4. generation medium fast trench IGBT
- CAL4F = Soft switching 4. generation CAL-diode
- Enhanced 900A free-wheeling diode
- With integrated gate resistor
- Isolated copper baseplate using DBC technology (Direct Bonded Copper)
- UL recognized, file no. E63532

Remarks

- Case temperature limited to $T_c = 125^\circ\text{C}$ max
- Recommended $T_{op} = -40 \dots +150^\circ\text{C}$
- Product reliability results valid for $T_j = 150^\circ$



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Absolute Maximum Ratings				
Symbol	Conditions		Values	Unit
IGBT				
V_{CES}	$T_j = 25^\circ\text{C}$		1200	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	913	A
		$T_c = 80^\circ\text{C}$	702	A
I_{Cnom}			600	A
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$		1800	A
V_{GES}			-20 ... 20	V
t_{psc}	$V_{CC} = 800\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 1200\text{ V}$	$T_j = 150^\circ\text{C}$	10	μs
T_j			-40 ... 175	$^\circ\text{C}$
Inverse diode				
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	54	A
		$T_c = 80^\circ\text{C}$	41	A
I_{Fnom}			50	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$		100	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$		180	A
T_j			-40 ... 175	$^\circ\text{C}$
Freewheeling diode				
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	936	A
		$T_c = 80^\circ\text{C}$	695	A
I_{Fnom}			900	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$		1800	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$		4320	A
T_j			-40 ... 175	$^\circ\text{C}$
Module				
$I_{t(RMS)}$			500	A
T_{stg}			-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50 Hz, $t = 1\text{ min}$		2500	V

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
$V_{CE(sat)}$	$I_C = 600\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	1.80	2.05		V
		$T_j = 150^\circ\text{C}$	2.20	2.42		V
V_{CE0}	chipllevel	$T_j = 25^\circ\text{C}$	0.80	0.90		V
		$T_j = 150^\circ\text{C}$	0.70	0.80		V
r_{CE}	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	1.67	1.92		$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	2.5	2.7		$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 24\text{ mA}$		5	5.8	6.5	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25^\circ\text{C}$			5	mA
		$T_j = 150^\circ\text{C}$			-	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		37.2		nF
C_{oes}		$f = 1\text{ MHz}$		2.32		nF
C_{res}		$f = 1\text{ MHz}$		2.04		nF
Q_G	$V_{GE} = -8\text{ V} \dots +15\text{ V}$			3400		nC
R_{Gint}	$T_j = 25^\circ\text{C}$			1.3		Ω



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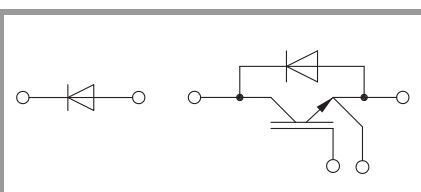
Features

- IGBT4 = 4. generation medium fast trench IGBT
- CAL4F = Soft switching 4. generation CAL-diode
- Enhanced 900A free-wheeling diode
- With integrated gate resistor
- Isolated copper baseplate using DBC technology (Direct Bonded Copper)
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Remarks

- Case temperature limited to $T_c = 125^\circ\text{C}$ max
- Recommended $T_{op} = -40 \dots +150^\circ\text{C}$
- Product reliability results valid for $T_j = 150^\circ$

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	$T_j = 150^\circ\text{C}$		195		ns
t_r	$I_C = 600\text{ A}$	$T_j = 150^\circ\text{C}$		91		ns
E_{on}	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$		81		mJ
	$R_{G\ on} = 2\ \Omega$					
$t_{d(off)}$	$R_{G\ off} = 2\ \Omega$	$T_j = 150^\circ\text{C}$		695		ns
t_f	$di/dt_{on} = 6000\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		131		ns
	$di/dt_{off} = 5200\text{ A}/\mu\text{s}$					
E_{off}		$T_j = 150^\circ\text{C}$		83		mJ
$R_{th(j-c)}$	per IGBT				0.049	K/W
Inverse diode						
$V_F = V_{EC}$	$I_F = 50\text{ A}$	$T_j = 25^\circ\text{C}$		2.41	2.74	V
	$V_{GE} = 0\text{ V}$	$T_j = 150^\circ\text{C}$		2.45	2.79	V
	chiplevel					
V_{F0}		$T_j = 25^\circ\text{C}$		1.30	1.50	V
	chiplevel	$T_j = 150^\circ\text{C}$		0.90	1.10	V
r_F		$T_j = 25^\circ\text{C}$		22	25	m Ω
	chiplevel	$T_j = 150^\circ\text{C}$		31	34	m Ω
I_{RRM}	$I_F = 50\text{ A}$	$T_j = 150^\circ\text{C}$				A
Q_{rr}	$di/dt_{off} = 5500\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$				μC
	$V_{GE} = \pm 15\text{ V}$					
E_{rr}	$V_{CC} = 600\text{ V}$	$T_j = 150^\circ\text{C}$				mJ
$R_{th(j-c)}$	per diode				1	K/W
Freewheeling diode						
$V_F = V_{EC}$	$I_F = 900\text{ A}$	$T_j = 25^\circ\text{C}$		2.14	2.46	V
	$V_{GE} = 0\text{ V}$	$T_j = 150^\circ\text{C}$		2.07	2.38	V
	chiplevel					
V_{F0}		$T_j = 25^\circ\text{C}$		1.3	1.5	V
	chiplevel	$T_j = 150^\circ\text{C}$		0.9	1.1	V
r_F		$T_j = 25^\circ\text{C}$		0.93	1.07	m Ω
	chiplevel	$T_j = 150^\circ\text{C}$		1.30	1.42	m Ω
I_{RRM}	$I_F = 600\text{ A}$	$T_j = 150^\circ\text{C}$		384		A
Q_{rr}	$di/dt_{off} = 5500\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		83		μC
	$V_{GE} = \pm 15\text{ V}$					
E_{rr}	$V_{CC} = 600\text{ V}$	$T_j = 150^\circ\text{C}$		47		mJ
$R_{th(j-c)}$	per diode				0.07	K/W
Module						
L_{CE}				15		nH
R_{CC+EE}	measured per switch	$T_C = 25^\circ\text{C}$		0.18		m Ω
		$T_C = 125^\circ\text{C}$		0.22		m Ω
$R_{th(c-s)}$	calculated without thermal coupling			0.02	0.038	K/W
M_s	to heat sink M6			3	5	Nm
M_t	to terminals M6			2.5	5	Nm
						Nm
w					310	g



GAE

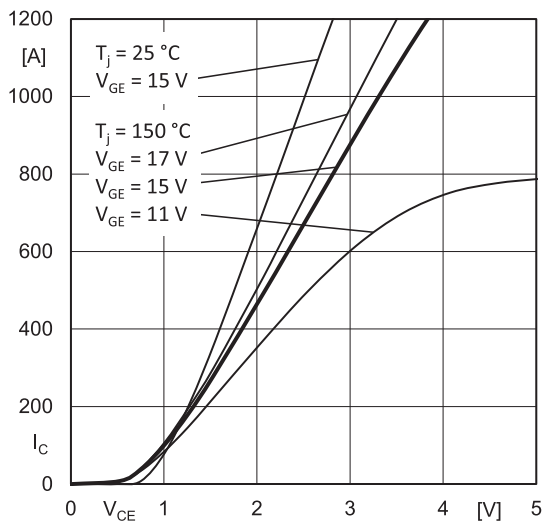


Fig. 1: Typ. output characteristic, inclusive $R_{CC'+EE'}$

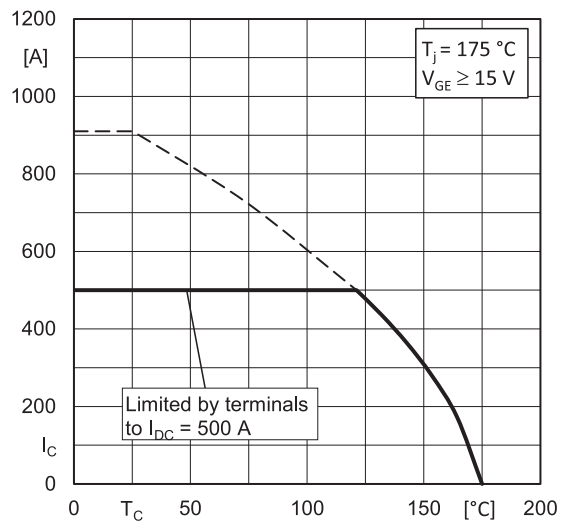


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

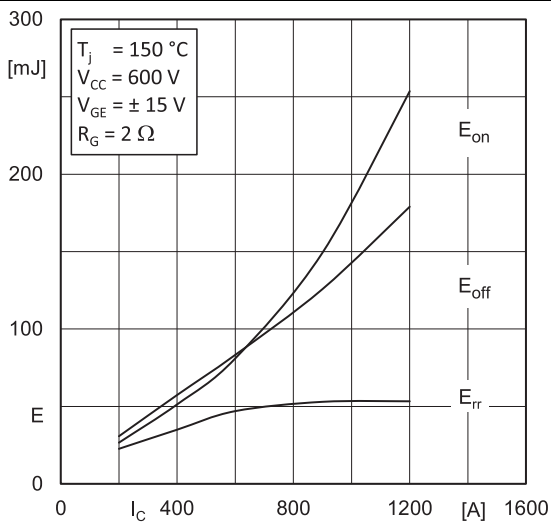


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

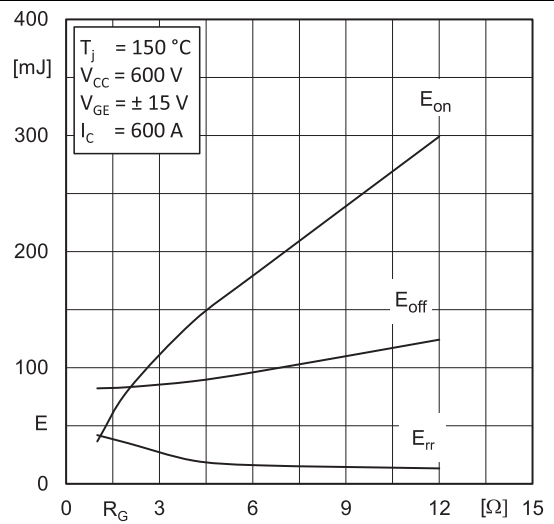


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

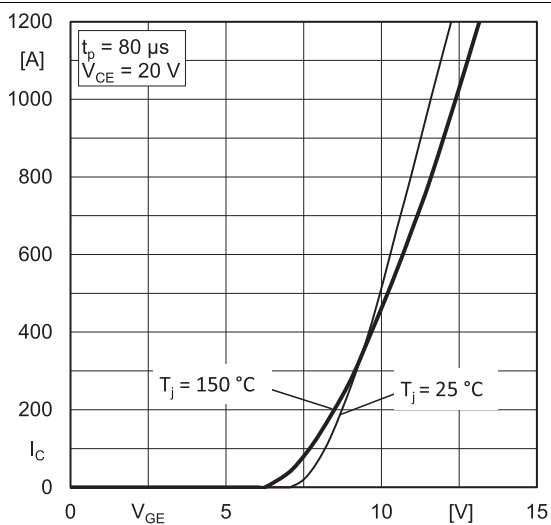


Fig. 5: Typ. transfer characteristic

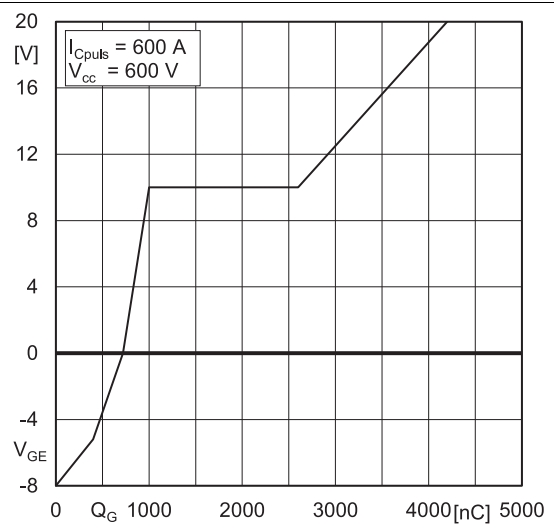


Fig. 6: Typ. gate charge characteristic

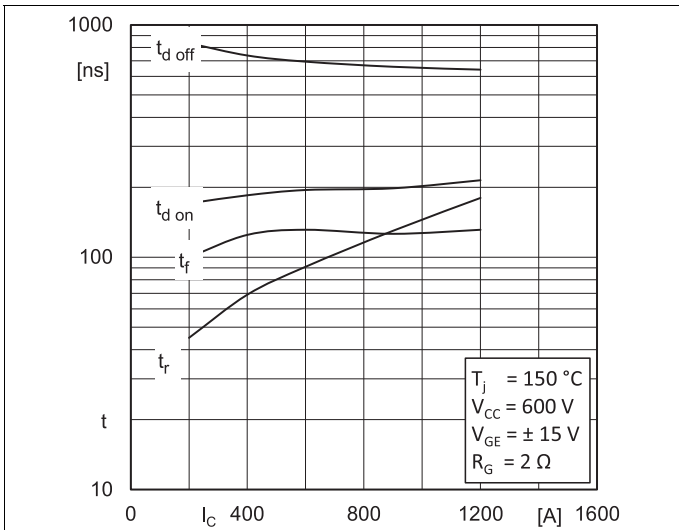


Fig. 7: Typ. switching times vs. I_C

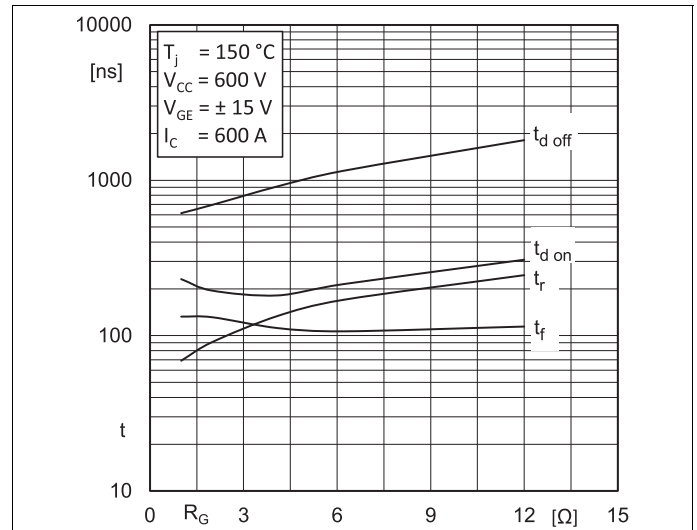


Fig. 8: Typ. switching times vs. gate resistor R_G

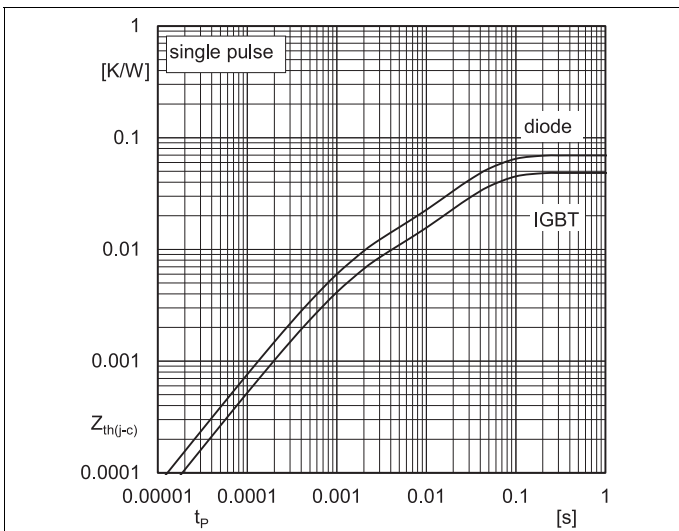


Fig. 9: Transient thermal impedance

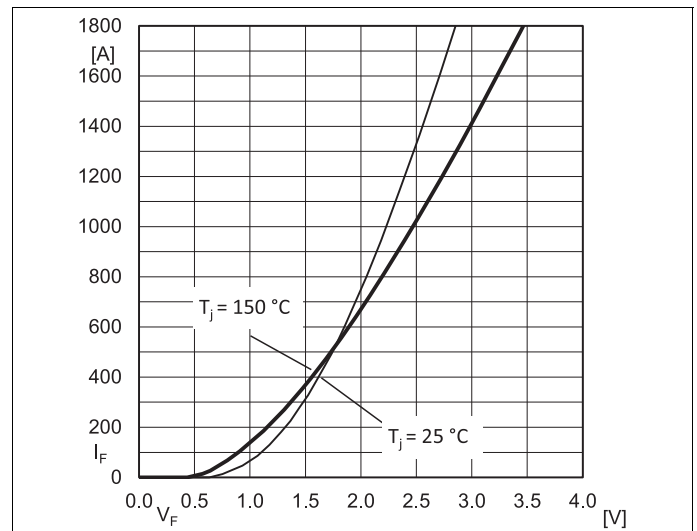


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC+EE'}$

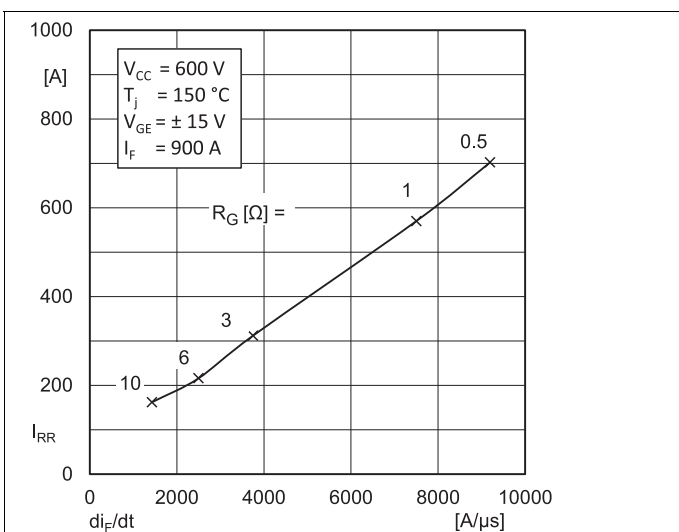


Fig. 11: CAL diode peak reverse recovery current

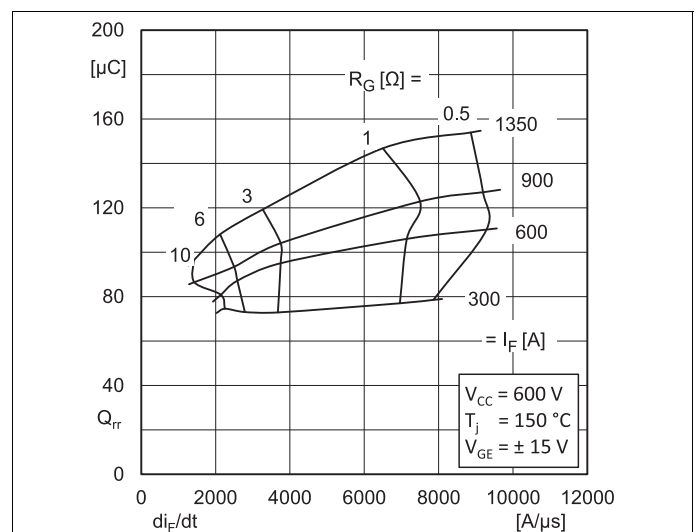


Fig. 12: Typ. CAL diode peak reverse recovery charge

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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